

NOTICE - WHEN GOVERNMENT DRAWINGS, SPECIFICATIONS, OR OTHER DATA ARE USED FOR ANY PURPOSE OTHER THAN IN CONNECTION WITH A DEFINITELY RELATED GOVERNMENT PROCUREMENT OPERATION, THE UNITED STATES GOVERNMENT THEREBY INCURS NO RESPONSIBILITY FOR ANY OBLIGATION WHATSOEVER, AND THE FACT THAT THE GOVERNMENT MAY HAVE FORMULATED, FURNISHED, OR IN ANY WAY SUPPLIED THE SAID DRAWINGS, SPECIFICATIONS OR OTHER DATA IS NOT TO BE REGARDED BY IMPLICATION OR OTHERWISE AS IN ANY MANNER LICENSEING THE HOLDER OR ANY OTHER PERSON OR CORPORATION, OR CONVEYING ANY RIGHTS OR PERMISSION TO MANUFACTURE, USE OR SELL ANY PATENTED INVENTION THAT MAY IN ANY WAY BE RELATED THERETO.

REQUIREMENTS:

1. GENERAL:

- INTERPRET DRAWING IN ACCORDANCE WITH STANDARDS PRESCRIBED BY MIL-D-70327.
- UNITS SHALL MEET THE REQUIREMENTS OF MIL-S-19500 EXCEPT AS, AND IN ADDITION TO THE REQUIREMENTS, SPECIFIED HEREIN.
- SUPPLIER SHALL CONFORM TO THE QUALITY ASSURANCE PROVISIONS CONTAINED IN MD 1015404, CLASS 2.
- UNITS SHALL BE CAPABLE OF MEETING THE QUALIFICATION REQUIREMENTS OF MD 1002051.
- MARKING:

(1) PARTS SHALL BE PERMANENTLY AND LEGIBLY MARKED, IN ACCORDANCE WITH MD 1002019, WITH THE NASA PART NUMBER (DRAWING NUMBER AND REVISION LETTER) OR AS MANY SIGNIFICANT DIGITS AS POSSIBLE (E.G. 6323). OTHER MARKING SUCH AS MANUFACTURER'S IDENTIFICATION AND TYPE NUMBER IS PERMISSIBLE.

(2) PREPARATION FOR DELIVERY SHALL BE IN ACCORDANCE WITH MD 1002215, CLASS I, CODE 2.

(3) MARKING OF SHIPPING CONTAINERS SHALL CONFORM TO THE MARKING OF UNIT AND INTERMEDIATE PACKAGES AND THE METHODS OF MARKING AS SPECIFIED IN MD 1002215.

2. ACCEPTANCE AND INSPECTION:

A. MECHANICAL PROPERTIES:

(1) DIMENSIONS: AS DELINEATED HEREIN.

(2) SEAL TEST: THE UNITS SHALL BE SUBJECTED TO A HELIUM OR RADIFLO LEAK DETECTION TEST WITH A SENSITIVITY OF AT LEAST 1×10^{-8} CC/ATM/SEC AND A HOT GLYCERINE BUBBLE TEST FOR GROSS LEAKS. THE LEAK TEST SHALL BE PERFORMED IN ACCORDANCE WITH MIL-STD-202C METHOD 112. TEST CONDITION C SHALL BE USED FOR THE HELIUM OR RADIFLO TEST. TEST CONDITION A SHALL BE USED FOR THE GROSS LEAK TEST EXCEPT THAT GLYCERINE SHALL REPLACE THE MINERAL OIL. A LEAKAGE RATE OF 1×10^{-6} CC/ATM/SEC OR GREATER SHALL CONSTITUTE A FAILURE.

B. ELECTRICAL CHARACTERISTICS: PER TABLES I, II, AND III AS LISTED BELOW:

(1) PRE-ELECTRICAL TEST PROCEDURE: ON LOTS OF 500 OR LESS, THE TESTS OF TABLE I SHALL BE PERFORMED IN THE SEQUENCE INDICATED BEFORE THE TESTS OF TABLE II.

(2) ELECTRICAL TESTING: THE TESTS LISTED IN TABLE II SHALL BE PERFORMED AS LISTED BELOW:

COLLECTOR CUTOFF CURRENT
COLLECTOR-BASE BREAKDOWN VOLTAGE
EMITTER-BASE BREAKDOWN VOLTAGE
EMITTER-BASE REVERSE CURRENT
COLLECTOR-EMITTER SUSTAINING VOLTAGE
COLLECTOR-EMITTER CURRENT
COLLECTOR-EMITTER THRESHOLD CURRENT
DIRECT CURRENT GAIN
BASE-EMITTER SATURATION VOLTAGE
COLLECTOR-EMITTER SATURATION VOLTAGE
COLLECTOR CAPACITANCE
TURN-ON AND TURN-OFF TIME

(3) QUALITY DEMONSTRATION TESTING:

PER TABLE III ON LOTS MORE THAN 500 UNITS USING ACCEPTABLE UNITS FROM SUBGROUP 2 OF TABLE II FOR SUBGROUP 2, 3, & 4 OF TABLE III. SUBGROUPS 1 & 5 MAY USE ELECTRICAL REJECTS FROM THE SAME LOT.

1006323

VENDOR SUPPLIED DATA: EACH SHIPMENT OF PARTS SHALL BE ACCOMPANIED BY THE FOLLOWING DOCUMENTATION.

- CERTIFICATE OF COMPLIANCE WITH LEAD MATERIALS REQUIREMENT.
- CERTIFICATE OF COMPLIANCE WITH MD 1015404, CLASS 2.
- A CERTIFICATE OF COMPLIANCE WITH PARA 2.C (1) OR 2.C(3). UNITS USED IN QUALITY DEMONSTRATION TESTS OF TABLE III WILL NOT BE SHIPPED AS PART OF THE DELIVERY SCHEDULE BUT WILL BE FORWARDED UNDER SEPARATE COVER WITH TEST DATA FOR EACH LOT SHIPMENT.

3. DESIGN:

A. STORAGE LIFE: INDEFINITE WHEN STORED AT TEMPERATURES BETWEEN -65°C AND $+150^{\circ}\text{C}$.

B. ABSOLUTE MAXIMUM RATINGS AT 25°C AMBIENT.

- COLLECTOR-EMITTER VOLTAGE (V_{CE0}): 40 VDC
- COLLECTOR-BASE VOLTAGE (V_{CB0}): 60 VDC
- EMITTER-BASE VOLTAGE (V_{EB0}): 5 VDC
- COLLECTOR CURRENT (I_C): 600 MILLIAMPERES
- THERMAL RESISTANCE, JUNCTION-CASE (θ_{JC}): 50°C/WATT
- THERMAL RESISTANCE, JUNCTION-AMBIENT (θ_{JA}): 350°C/WATT
- TEMP. RANGE, JUNCTION, OPERATING: -65°C TO $+150^{\circ}\text{C}$
- TEMP. RANGE, STORAGE: -65°C TO $+150^{\circ}\text{C}$

C. CONSTRUCTION:

- SEMICONDUCTOR: SILICON PLANAR EPITAXIAL NPN
- CASE: METAL CASE AND METAL HEADER HERMETICALLY SEALED (JEDEC TO -18)
- COLLECTOR SHALL BE ELECTRICALLY CONNECTED TO THE CASE INTERNALLY.
- LEAD MATERIAL: WELDABLE, GOLD PLATED, ANNEALED IRON-NICKEL-COBALT (KOVAR) ALLOY IN ACCORDANCE WITH MD 1015402.

D. QUALITY ASSURANCE REQUIREMENTS:

- LOT DEFINITION: A GROUP OF PARTS IN A SINGLE PROCUREMENT SELECTED FROM A SINGLE CONTINUOUS PRODUCTION RUN USING LIKE MATERIALS WHICH ARE CONTROLLED USING A PROCESS WHICH IS THE SAME FROM THE BEGINNING TO THE END OF THE RUN.
- INSPECTION CONDITIONS: UNLESS OTHERWISE SPECIFIED, ALL INSPECTIONS SHALL BE MADE AT AN AMBIENT TEMPERATURE OF $+25^{\circ} \pm 3^{\circ}\text{C}$.

PROCURE ONLY FROM APPROVED SOURCES LISTED IN MD 1002034 FOR THIS DRAWING.

UNLESS OTHERWISE SPECIFIED DIMENSIONS ARE IN INCHES CAPACITOR VALUES ARE IN μf RESISTOR VALUES ARE IN OHMS TOLERANCES ON FRACTIONS DECIMALS ANGLES $\pm$ $\pm$ $\pm$ DO NOT SCALE THIS DRAWING		MIT INSTRUMENTATION LAB CAMBRIDGE, MASS.		MANNED SPACECRAFT CENTER HOUSTON, TEXAS	
MATERIAL		DRAWN <i>[Signature]</i> 10/1/65 CHECKED <i>[Signature]</i> 10/1/65 APPROVED <i>[Signature]</i> 10/1/65 APPROVED <i>[Signature]</i> 10/1/65		TRANSISTOR, SILICON, TYPE NPN, SWITCHING	
NEXT ASSY USED ON		APPROVED MIT <i>[Signature]</i> 10/1/65 APPROVED MSC <i>[Signature]</i> 10/1/65		SPECIFICATION CONTROL DRAWING	
APPLICATION		CODE IDENT NO. 80230 SIZE C DATE SCALE		DRAWING NO. 1006323	
		SHEET 1 OF 4			

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TABLE I

PRE-ELECTRICAL TEST PROCESSING

TEST	MIL-STD-750 TEST CONDITIONS	LOT	
		1 TO 500	OVER 500
THERMAL SHOCK *	METHOD 1056, CONDITION B (+150°C TO -65°C, 3 CYCLES)	100%	NO REQUIREMENT
STORAGE LIFE * (HIGH TEMPERATURE STABILIZATION)	METHOD 1031, Tstg = 150° ± 5°C, 72 ⁺⁸ ₋₄ HOURS		
CONSTANT ACCELERATION *	METHOD 2006 (20,000 G) Y AXIS		
POWER, BURN-IN *	METHOD 1026 P = 350 MILLIWATTS V _{CE} = +20.0 VOLTS MINIMUM T _A = +22°C MIN IN FREE AMBIENT AIR t = 168 ⁺¹² ₋₆ HOURS		
SEAL TEST *	SEE NOTE 2.8		

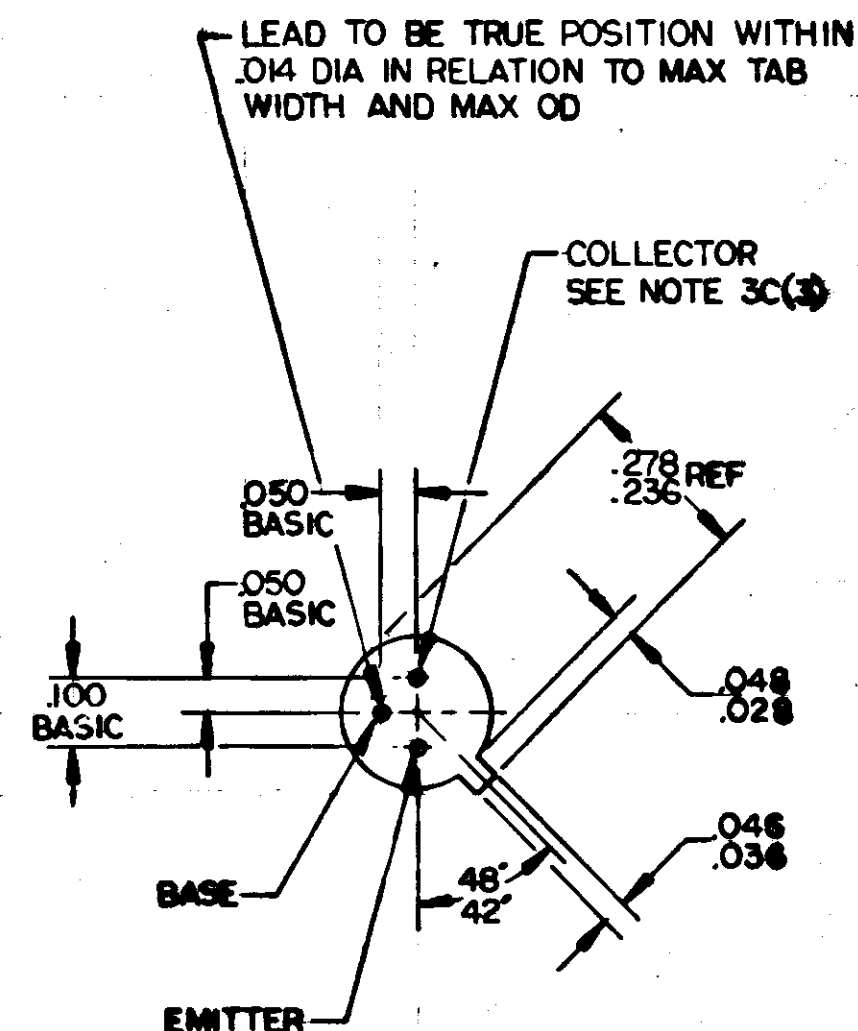
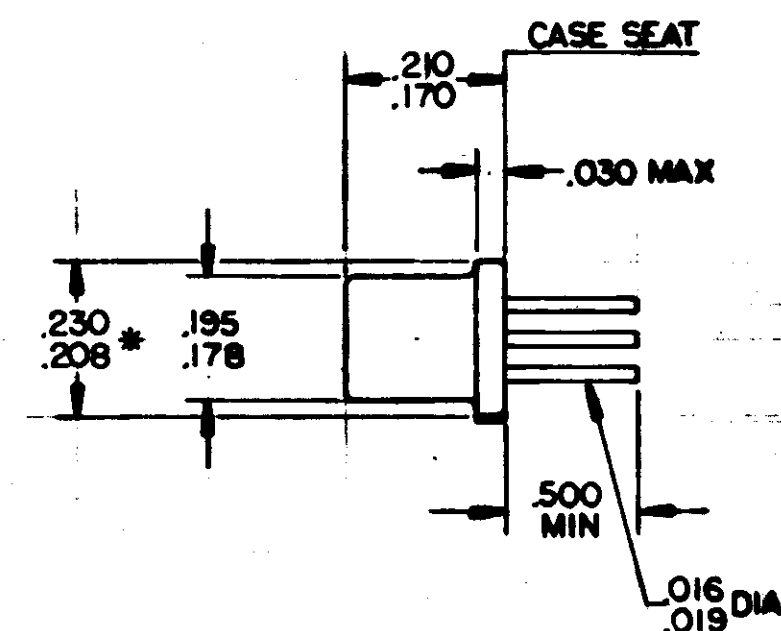
*TEST TO BE PERFORMED IN ORDER INDICATED

**PULSE ≤ 300μ SECS AT ≤ 2% DUTY CYCLE.

***LTPD OF λ PER MIL-S-19500D, TABLE C1 OR C11

****THE PARAMETER MEASURED MAY NOT CHANGE ANY GREATER THAN THE PERCENTAGE SPECIFIED BETWEEN THE INITIAL VALUE AND THE END OF TEST VALUE. VALUES OF COLLECTOR AND EMITTER CUTOFF CURRENTS LESS THAN 10 NANOAMPERES MAY BE CONSIDERED TO BE 10 NANOAMPERES FOR CALCULATING PERCENTAGE CHANGE.

● CURRENTS TO WITHIN ±10%



MASTER

		UNLESS OTHERWISE SPECIFIED DIMENSIONS ARE IN INCHES TOLERANCES ON
		FRACTIONS DECIMALS ANGLES
		± ± ±
		DO NOT SCALE THIS DRAWING
		MATERIAL
		SEE NOTE
		HEAT TREATMENT
		NONE
		FINAL FINISH
		NONE
NEXT ASSY	USED ON	
APPLICATION		

QTY REQD	PART OR IDENTIFYING NO.	NOMENCLATURE OR DESCRIPTION	FIND NO.
LIST OF MATERIALS			
MIT INSTRUMENTATION LAB CAMBRIDGE, MASS.		MANNED SPACECRAFT CENTER HOUSTON, TEXAS	
DRAWN <i>[Signature]</i> DATE <i>2/28/65</i>		TRANSISTOR, SILICON, TYPE NPN, SWITCHING	
CHECKED <i>[Signature]</i> DATE <i>2/28/65</i>		SPECIFICATION CONTROL DRAWING	
APPROVAL <i>[Signature]</i>			
APPROVAL <i>[Signature]</i>			
NASA APPROVAL <i>[Signature]</i>		CODE IDENT NO. 80230	NASA DRAWING NO. 1006323
MIT APPROVAL <i>[Signature]</i>		SIZE C	
MIT APPROVAL		SCALE NONE	WT
		SHEET 2 OF 4	

NOTICE - WHEN GOVERNMENT DRAWINGS, SPECIFICATIONS, OR OTHER DATA ARE USED FOR ANY PURPOSE OTHER THAN IN CONNECTION WITH A DEFINITELY RELATED GOVERNMENT PROCUREMENT OPERATION, THE UNITED STATES GOVERNMENT THEREBY INCURS NO RESPONSIBILITY NOR ANY OBLIGATION WHATSOEVER, AND THE FACT THAT THE GOVERNMENT MAY HAVE FORMULATED, FURNISHED, OR IN ANY WAY SUPPLIED THE SAID DRAWINGS, SPECIFICATIONS OR OTHER DATA IS NOT TO BE REGARDED BY IMPLICATION OR OTHERWISE AS IN ANY MANNER LICENSING THE HOLDER OR ANY OTHER PERSON OR CORPORATION, OR CONVERTING ANY RIGHTS OR PERMISSION TO MANUFACTURE, USE, OR SELL ANY PATENTED INVENTION THAT MAY IN ANY WAY BE RELATED THERETO.

TABLE II

ACCEPTANCE INSPECTION

ACCEPTANCE INSPECTION							
TEST	SYMBOL	MIL-STD-750 TEST CONDITIONS T _A = 25° ± 3°C UNLESS SPECIFIED	LIMIT		UNITS	LOT	
			MIN	MAX		1 TO 500	OVER 500
SUBGROUP 1							
VISUAL AND MECHANICAL EXAMINATION		METHOD 2071				LTPD***= 10 MAX ACC NO.= 3	LTPD***= 10 MAX ACC NO. = 3
SUBGROUP 2							
COLLECTOR CUTOFF CURRENT	I _{CBO}	V _{CB} = 30 V; I _E = 0		100	mA	100%	LTPD**= 2 (COMBINED) MAX ACC NO. = 3
COLLECTOR CUTOFF CURRENT 150°C	I _{CBO}	V _{CB} = 30 V; I _E = 0; T _A = +150°C		200	μA		
COLLECTOR-BASE BREAKDOWN VOLTAGE	BV _{CBO}	I _C = 100μA; I _E = 0	60		V		
EMITTER-BASE REVERSE CURRENT	I _{EBO}	V _{EB} = 3 V; I _C = 0		100	mA		
EMITTER-BASE BREAKDOWN VOLTAGE	BV _{EBO}	I _E = 100μA; I _C = 0	5		V		
COLLECTOR-EMITTER SUSTAINING VOLTAGE**	V _{CEO} SUST	I _C = 30mA PULSED I _B = 0	30		V		
COLLECTOR-EMITTER BREAKDOWN	V _{CEO}	I _C = 1mA; I _B = 0	40		V		
COLLECTOR-EMITTER CURRENT RES. RETURN	J _{CER}	V _{CE} = 30 V; R _{BE} = 100 K		10	μA		
COLLECTOR-EMITTER THRESHOLD CURRENT	I _{CEX}	V _{BE} = +0.4V; V _{CE} = 30V		10	μA		
DC CURRENT GAIN **	h _{FE}	I _C = +500 mA; V _{CE} = +10 V	25				
DC CURRENT GAIN **	h _{FE}	I _C = +150 mA; V _{CE} = +10 V	40	120			
DC CURRENT GAIN **	h _{FE}	I _C = +10 mA; V _{CE} = +10 V	30				
BASE-EMITTER SATURATION VOLTAGE **	V _{BE} SAT	I _C = 500 mA; I _B = 50 mA	1.10	1.30	V		
COLLECTOR-EMITTER SATURATION VOLTAGE**	V _{CE(sat)}	I _C = 150 mA; I _B = 15 mA		0.40	V		
COLLECTOR-EMITTER SATURATION VOLTAGE**	V _{CE(sat)}	I _C = 500 mA; I _B = 50 mA		1.0	V		
COLLECTOR CAPACITANCE	C _{ob}	V _{CB} = -10 V; I _E = 0; F = 0.14 mc		8	PF		
TURN ON TIME	t _{on}	I _{B1} ≈ 15 mA; I _C ≈ 150 mA t _w > 400 nsec 2% DUTY CYCLE		20	NSEC	LTPD***=5 MAX ACC NO =0	LTPD***=5 MAX ACC NO =0
TURN OFF TIME	t _{off}	I _{B1} = I _{B2} ≈ 15 mA; I _C ≈ 150 mA t _w > 400 nsec 2% DUTY CYCLE		40	NSEC		

* LTPD PER MIL-S-195000, TABLE III OR II

NOTED

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NEXT ASSY	USED ON	
APPLICATION		

QTY REQD	PART OR IDENTIFYING NO.	MATERIAL OR NOTES	NOMENCLATURE OR DESCRIPTION	FIND NO.
LIST OF MATERIALS				
MIT INSTRUMENTATION LAB CAMBRIDGE, MASS.		MANNED SPACECRAFT CENTER HOUSTON, TEXAS		
DRAWN	9/2/65	TRANSISTOR, SILICON, TYPE NPN, SWITCHING SPECIFICATION CONTROL DRAWING		
CHECKED	10 Feb 65			
APPROVED				
APPROVED	18 Mar 65			
APPROVED MIT	3/14/65	CODE IDENT NO. 80230	SIZE C	DRAWING NO. 1006323
APPROVED MSC	DATE	SCALE	SHEET 3 OF 4	

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TABLE III

TEST	MIL-STD-750 TEST CONDITIONS	LOT	
		1 TO 500	OVER 500
SUBGROUP 1 PHYSICAL DIMENSIONS	METHOD 2066	NO REQUIREMENTS	LTPD ^{***} = 20 MAX ACC NO. = 1
SUBGROUP 2** THERMAL SHOCK	METHOD 1056.1 (+150 °C TO -65 °C, 5 CYCLES)		LTPD ^{***} = 10 (COMBINED) MAX ACC NO. = 3
SEAL TEST	SEE NOTE 2.B		
SUBGROUP 3** STORAGE LIFE	METHOD 1031.1 T _{stg} = 150 ° ± 5 °C, 1000 HOURS		LTPD ^{***} = 10 (COMBINED) MAX ACC NO. = 3
SHOCK	METHOD 2016.1 1500 G, 0.5 MSEC 5 BLOWS EACH IN X1, Y1, Y2, Z1 DIRECTIONS, 20 BLOWS TOTAL		
VIBRATION VARIABLE FREQUENCY	METHOD 2056, 30 G FROM 5 TO 2000 CPS LIMITED TO 0.12 DOUBLE AMPLITUDE, 3 CYCLES, 15 MINUTES PER CYCLE MINIMUM.		
CONSTANT ACCELERATION	METHOD 2006, 20,000 G Y AXIS		
SUBGROUP 4 OPERATION LIFE	METHOD 1026.1 P = 350 MILLIWATTS V _{CE} = +20 VOLTS MINIMUM T _A = +22 °C MIN IN FREE AMBIENT AIR t = 1000 HOURS	** = 10 MAX ACC NO. = 3	
SUBGROUP 5** LEAD TENSION (COND. A) LEAD FATIGUE (COND. B)	METHOD 2036.1 4 POUND LOAD FOR 10 SECONDS 3 ARCS	LTPD ^{***} = 20 (COMBINED) MAX ACC NO. = 3	

* SEE MIL-STD-883C FOR TEST PROCEDURES
** TESTS TO BE PERFORMED IN ORDER INDICATED

A 1006323

REVISIONS						
SYM	ZONE	DESCRIPTION	DR	CHK	DATE	APPROVED
-		INITIAL RELEASE CLASS A PER TDRR			17476	W.H.
A		REVISED PER TDRR 20619			8/17/65	W.H.

TABLE III (CONTINUED)

TEST	SYMBOL	TEST CONDITION	LIMIT
END POINTS FOR SUBGROUP 2 COLLECTOR CUTOFF CURRENT	I _{CB0} II (CO)	V _{CB} = +30 V, I _E = 0	±50% ****
EMITTER-BASE REVERSE CURRENT	I _{EB0}	V _{EB} = +3 V, I _C = 0	±50% ****
DC CURRENT GAIN	h _{FE}	V _{CE} = +10 V, I _C = 150 mA	±100% ****
END POINTS FOR SUBGROUPS 3 & 4 COLLECTOR CUTOFF CURRENT	I _{CB0} I0	V _{CB} = +30 V, I _E = 0	±100% ****
EMITTER-BASE REVERSE CURRENT	I _{EB0} I0	V _{EB} = +3 V, I _C = 0	±100% ****
DC CURRENT GAIN	h _{FE}	V _{CE} = +10 V, I _C = 150 mA	±200% ****

COLLECTOR CUTOFF CURRENT	I _{CB0}	V _{CB} = +40 V, I _E = 0	±100% *
EMITTER CUTOFF CURRENT	I _{EB0}	V _{EB} = +3 V, I _C = 0	±100% *
DC CURRENT GAIN	h _{FE}	V _{CE} = +10 V, I _C = 150 mA	±100% *

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POSTER

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		MATERIAL
NEXT ASSY	USED ON	
APPLICATION		

QTY REQD	PART OR IDENTIFYING NO.	MATERIAL OR NOTES	NOMENCLATURE OR DESCRIPTION	FIND NO.			
LIST OF MATERIALS							
MIT INSTRUMENTATION LAB CAMBRIDGE, MASS.		MANNED SPACECRAFT CENTER HOUSTON, TEXAS					
DRAWN <i>W. J. Jones</i> 9 FEB 65	TRANSISTOR, SILICON TYPE NPN, SWITCHING						
CHECKED <i>W. J. Jones</i> 10 FEB 65							
APPROVED <i>W. J. Jones</i>	SPECIFICATION CONTROL DRAWING						
APPROVED <i>W. J. Jones</i> 15 FEB 65							
APPROVED MIT <i>W. J. Jones</i>	CODE IDENT NO. 80230	SIZE C	DRAWING NO. 1006323				
APPROVED MSC <i>W. J. Jones</i>	DATE 3/12/65	SCALE	SHEET 4 OF 4				